

<b>Notice of References Cited</b>	Application/Control No. 10/564,249	Applicant(s)/Patent Under Reexamination MIYAWAKI ET AL.	
	Examiner Megann E. Vaughn	Art Unit 2859	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,559,643	05-2003	Miyoshi, Mitsuharu	324/309
*	B	US-6,867,590	03-2005	Carlini, Davide	324/309
*	C	US-6,483,305	11-2002	Miyamoto, Shoei	324/307
*	D	US-6,392,411	05-2002	Goto, Takao	324/309
*	E	US-2002/0050816	05-2002	Miyoshi, Mitsuharu	324/307
*	F	US-2002/0135366	09-2002	Heubes, Peter	324/307
*	G	US-2003/0160616	08-2003	Asano et al.	324/318
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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